

<b>Notice of References Cited</b>	Application/Control No. 10/626,011		Applicant(s)/Patent Under Reexamination DE WAAL, ABRAHAM B.	
	Examiner TUYETLIEN T. TRAN		Art Unit 2179	Page 1 of 1

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*	B	US-6,724,403 B1	04-2004	Santoro et al.	715/765
*	C	US-7,124,360 B1	10-2006	Drenttel et al.	715/205
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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